

Notice of References Cited	Application/Control No. 10/734,610		Applicant(s)/Patent Under Reexamination WEDEL ET AL.	
	Examiner ANNA DENG		Art Unit 2191	Page 1 of 1

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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)			
	U	Chen et al. "Automatic trace analysis for logic of constraints", June 2003, ACM, DAC '03, pages 460-465			
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.